

Issue Classification				Application/Control No.	Applicant(s)/Patent under Reexamination	
				10/764,283	CHAPMAN, THOMAS R.	
Examiner				Devin Hanan	Art Unit	
				3745		

ISSUE CLASSIFICATION

ORIGINAL				CROSS REFERENCE(S)							
CLASS	SUBCLASS	CLASS		SUBCLASS (ONE SUBCLASS PER BLOCK)							
416	185	415	206								
INTERNATIONAL CLASSIFICATION											
F	0	1	D	5/22	/	/	/	/	/	/	/
<i>Devin Hanan 4/14/2006</i>				<i>Edward K. Look 4/17/06</i>				Total Claims Allowed: 35			
Devin Hanan 4/14/2006 (Assistant Examiner) (Date)				EDWARD K. LOOK SUPREMO PATENT EXAMINER TECHNOLOGY CENTER 3700 (Primary Examiner) (Date)				O.G. Print Claim(s) 1			
K Cooper 4/20/06 (Legal Instruments Examiner) (Date)								O.G. Print Fig 2			

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
Final	Original	Final	Original	Final	Original	Final	Original
1	1	32	31	61	91	121	151
2	2	33	32	62	92	122	152
6	3	14	33	63	93	123	153
7	4	35	34	64	94	124	154
8	5	35	35	65	95	125	155
9	6	36	36	66	96	126	156
10	7	34	37	67	97	127	157
19	8	38	38	68	98	128	158
20	9	39	39	69	99	129	159
15	10	40	40	70	100	130	160
18	11	41	41	71	101	131	161
21	12	42	42	72	102	132	162
24	13	43	43	73	103	133	163
17	14	44	44	74	104	134	164
10	15	45	45	75	105	135	165
3	16	46	46	76	106	136	166
18	17	47	47	77	107	137	167
11	18	48	48	78	108	138	168
24	19	49	49	79	109	139	169
4	20	50	50	80	110	140	170
12	21	51	51	81	111	141	171
25	22	52	52	82	112	142	172
5	23	53	53	83	113	143	173
13	24	54	54	84	114	144	174
26	25	55	55	85	115	145	175
28	26	56	56	86	116	146	176
27	27	57	57	87	117	147	177
29	28	58	58	88	118	148	178
30	29	59	59	89	119	149	179
31	30	60	60	90	120	150	180